



Innovative 20nm Space FPGA Ceramic & Ruggedized Package Trends

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RT Kintex UltraScale Platform Announced in May 2020

High Bandwidth Compute Capability

Features

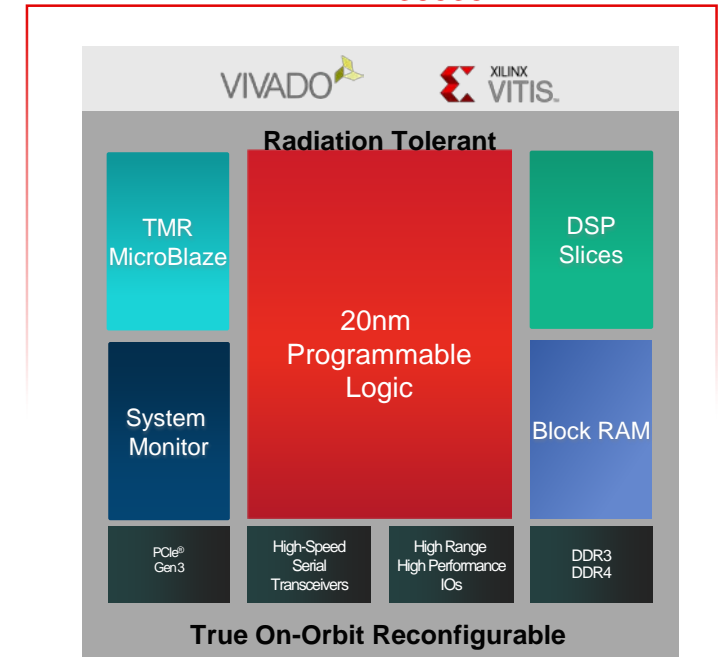
- ▶ 2760 DSP Slices: Multi-precision fixed and floating point modes
- ▶ 32 High Speed SERDES (12.5Gbps): 400Gbps aggregate BW
- ▶ Radiation Tolerance across all orbits TID >100Krad/si, SEL >80MeV-cm²/mg
- ▶ Robust 40x40 mm Ceramic Column Grid Array Packaging
- ▶ Machine Learning Ecosystem enables High Performance Edge Inference in Space

Meets Next Generation on Orbit Processing Needs

- ▶ Protos, Mechanical Samples: **NOW**
- ▶ Vivado SW, XPE*, Datasheet: **NOW**
- ▶ Production (Class B, Class Y): **Sept 2020**



MIL-PRF-38535



Process, Analyze & Reconfigure

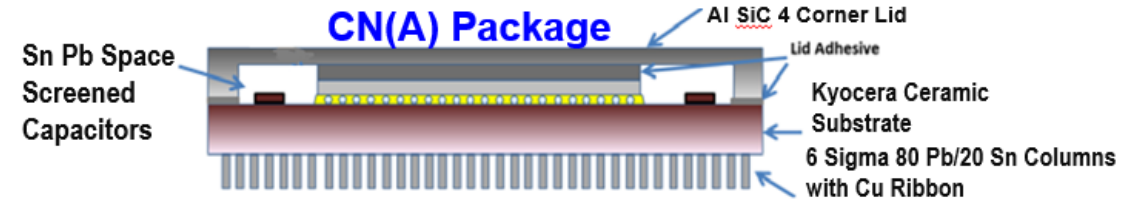
Introducing 20nm Technology: XQRKU060-CNA1509 Package

Package Details: 40x40 mm ceramic flip chip package with Pb/Sn Cu ribbon solder columns

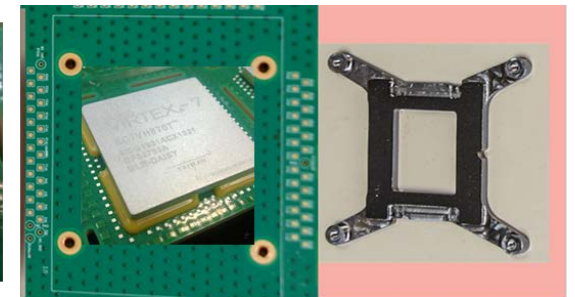
- Same package construction/columns as current XQR5VFX130-CN1752 45x45 mm package
- Qualification on track

Enhancing the Thermo-Mechanical Integrity for High G /Vibration Environment

- Introducing edge bonding to the package (Zymet UA2605-B)
- To eliminate any Mechanical crack between the package the PCB interconnect
- Enabling back bracket to stiffen the package in the System
- Introducing Dynamic mounting to apply constant pressure on the package during the life time
- Ensuring stable thermal contact between the package and the thermal solution



Bill Of Material & Suppliers	XQRKU060-CNA1509	XQR5VFX130-CN1752
C4 Bump	Eutectic Sn Pb	Same
Lid	4 corner AlSiC	Same
Substrate	Ceramic (Alumina)	Same
Chip Capacitors	Sn Pb with cap level space qual testing per MIL-PRF-32535	Same
Column	80 Pb/20 Sn with Cu ribbon	Same
Assembly Supplier	Kyocera San Diego	Same
Column Attach Supplier	6 Sigma	Same



Edge bonding passing 2500 cycles (see Zymet UA-2605-B Edge Bond Adhesive)

What are the options beyond 20 nm for Space?

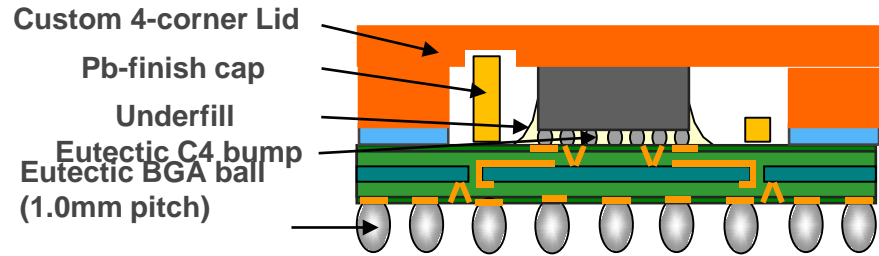
Ceramic running into design and technology bottlenecks

Feature	HTCC (SIRF POR)	LTCC (870T)	Organic	Comment
Process Temp	> 2000C	< 1000C	< 250C	
Dielectric Material	Alumina	Special Ceramic	Epoxy Silica filled (>80%)	
Metallization	Fused W or Mo	Fused Cu	Cu	Resistivity: Fused W >> Fused Cu >> Cu
Substrate CTE ppm/C	7 ppm/C	11-12 ppm/C	13-15 ppm/C	PCB CTE 17-21 ppm/C
PKG Type	Pin / CCGA	BGA / LGA	BGA / LGA	BGA assembly much easier
Lamination process	One-time	One-time	Sequential	
Via formation	Universal Punch tooling	Universal Punch Tooling	Laser drill	Organic via density >> Ceramic
Min. C4 pitch	180um	150um - 180um	110um	7nm is 130um min.
Min. Dielectric thickness	100um	75um*	25um	*50um maybe available 4 layers
Line/Space um	75um/75um min.	40um / 40um	10um / 10um	
Via/pad um	100um / 150um	50um / 100um	50um / 85um	
Advanced node designs	Not feasible	May be feasible with pitch fan-out and derating	Exists 14L – 18L	Technology/design not feasible PDN, X-talk metrics challenging to meet with Ceramic
Applying Mech Pressure	~10-15PSI	~10-15PSI	~30-50 PSI	Next Gen need to stand for high Thermo-mech solution
Thermal solution, RJA	~ 3 C/W	~3 C/W	~>1.5 C/W	Next Gen need more thermal performance
Power W(Flux W/cm2)	<= 12 (5W/Cm2)	<= 12 (5W/Cm2)	>+25W (7W/Cm2)	Next Gen need to have more Performance/W by Adding more hard IP

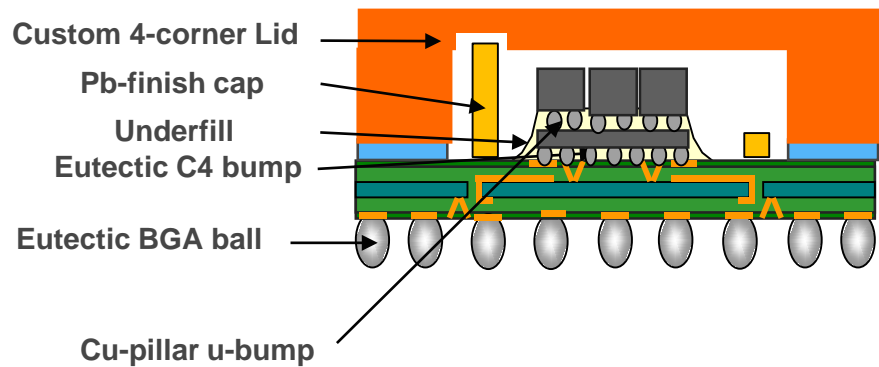
Ruggedized Organic Packaging for Non Space Applications

Current (In Production)

Monolithic 20nm/16nm

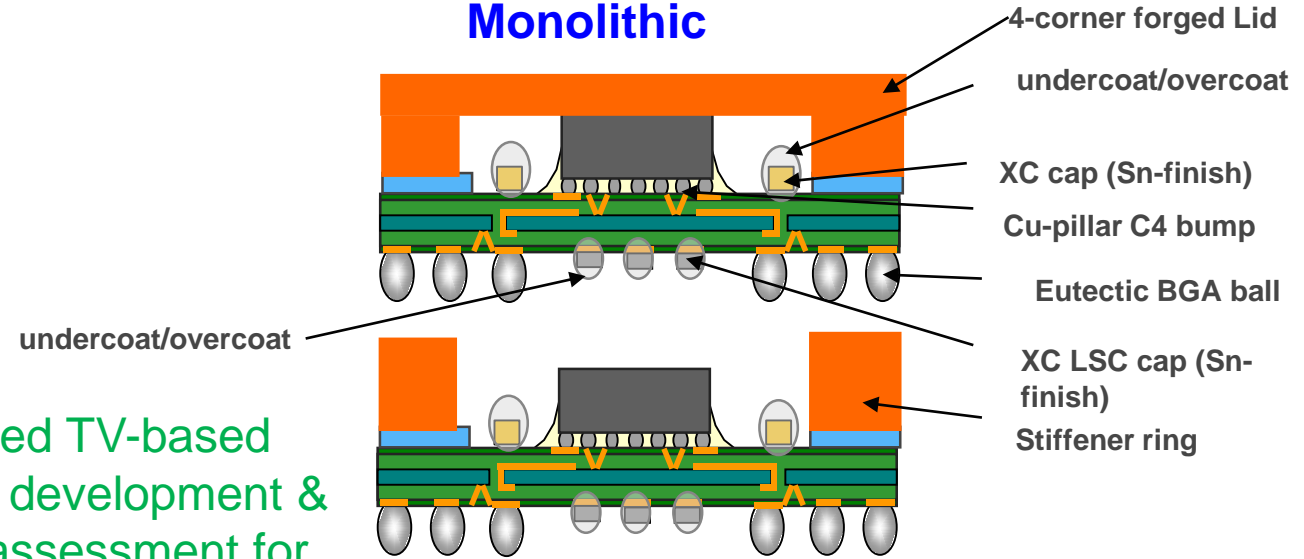


SSIT 20nm/16nm (non-HBM)

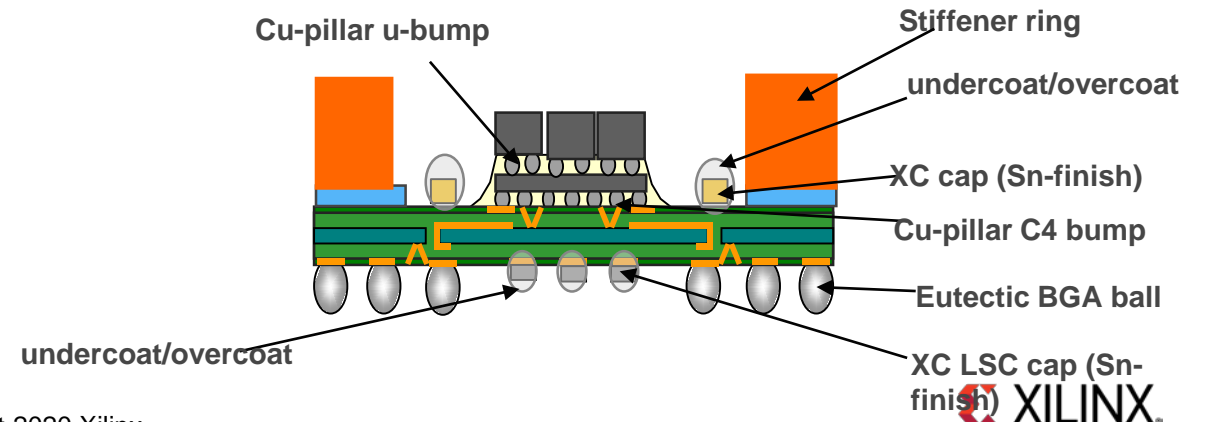


Future

Monolithic

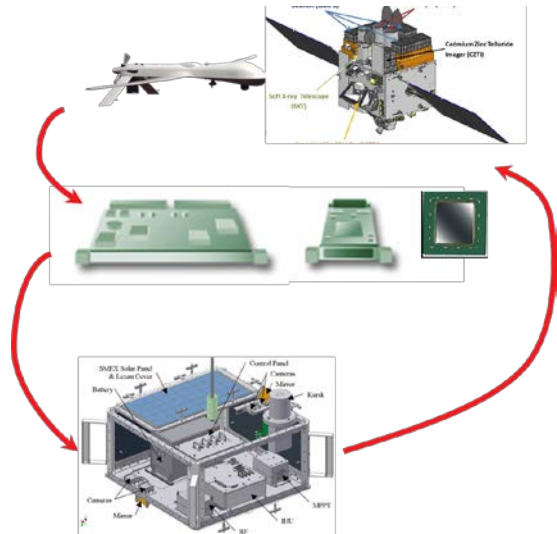


SSIT (non-HBM)



Completed TV-based technology development & reliability assessment for next generation solutions

Today Challenges were addressed in 20nm Technology

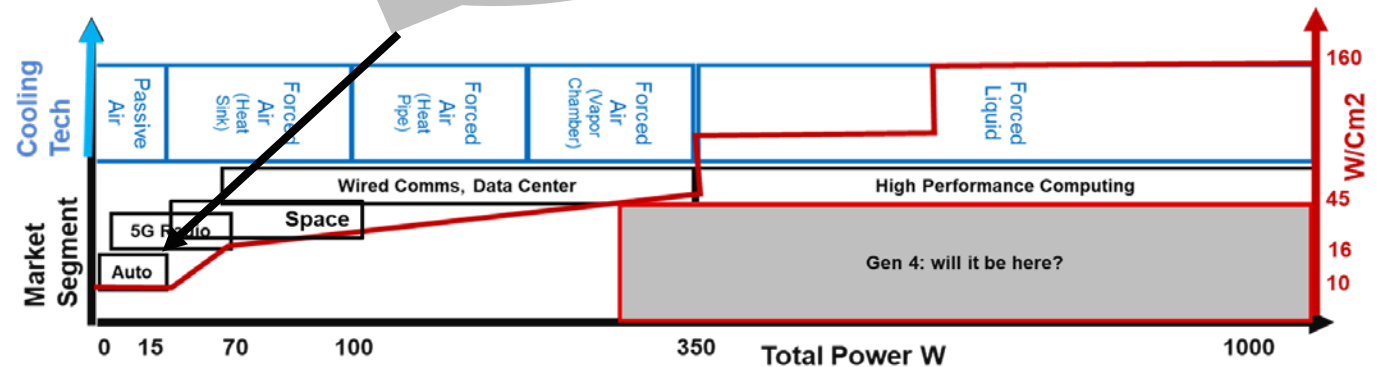


- ▶ Determine application requirements
 - Size, weight and power
 - →XLNX
- ▶ Select overall system parameters
 - →XLNX
- ▶ Assemble development vehicle
 - →COTS
- ▶ Design deployment system

Space PKG solution need to be architected based on:

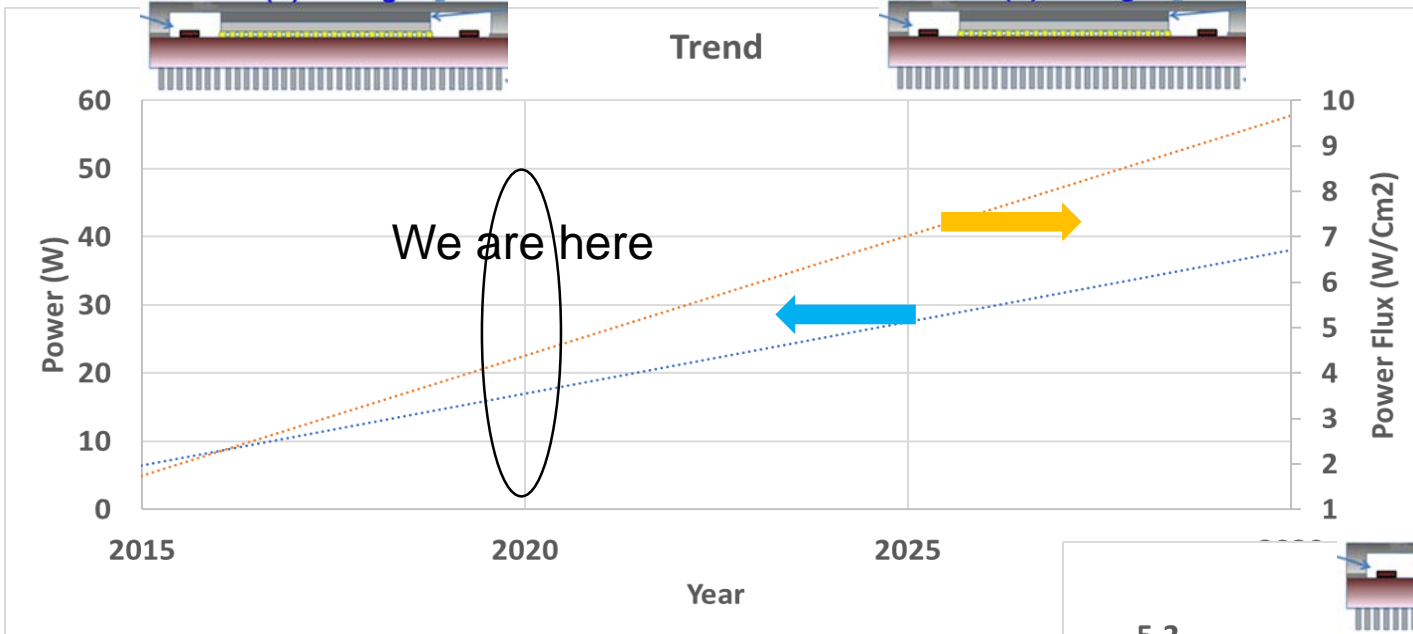
- Package Features
 - Interconnectivity
 - Line/spacing/Pad
 - Dielectric thickness
- Mechanical
 - Package structure
 - Assembly and Manufacture
- Thermal Management
 - Power Map;
 - Current Density
- Reliability

Where are we?

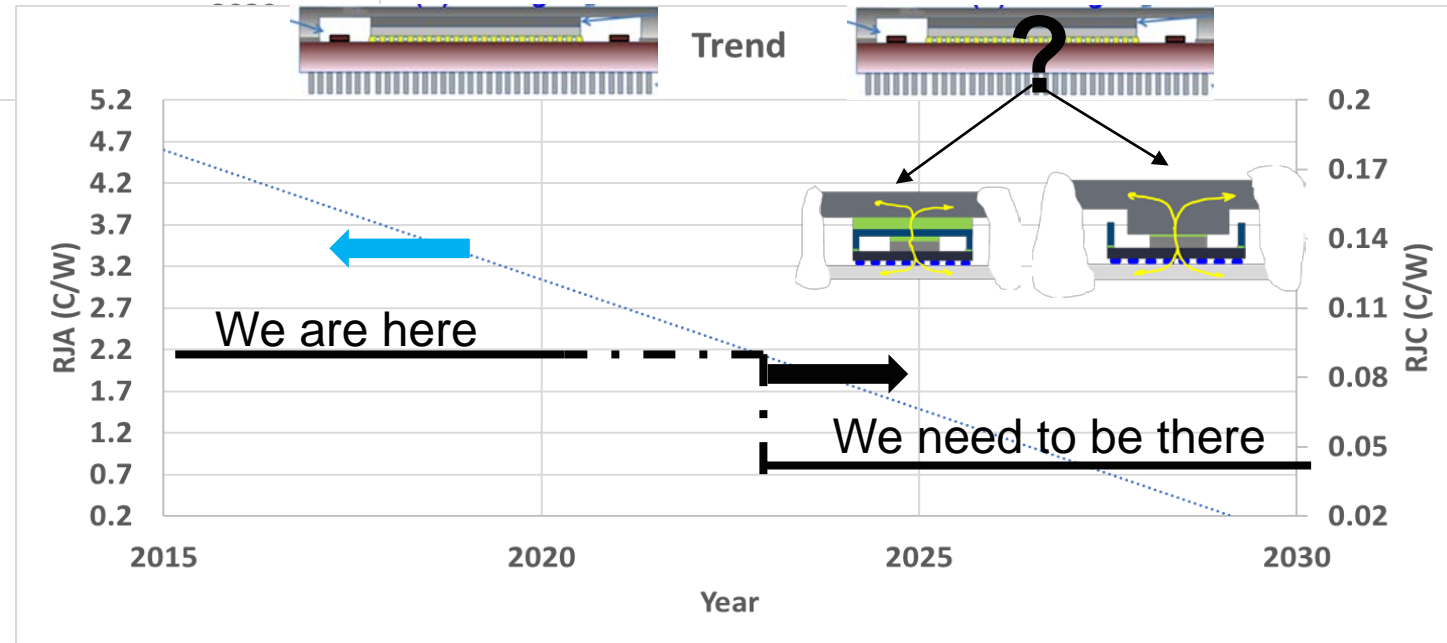


- Given all of the above
 - Can we extended thermal limit of FPGA in aerospace applications?

Past, Present, Future



We are ready for 20 nm and beyond



Adaptable.
Intelligent.

